U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,313,398	05-1994	Rohrer et al.	703/14
	B	US-6,154,716	11-2000	Lee, David C.	703/2
	C	US-6,271,579	08-2001	Going et al.	257/664
	D	US-6,141,634	10-2000	Flint et al.	703/18
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					.

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Opal, A, "Sampled data simulation of linear and nonlinear circuits," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol.: 15 Issue: 3 , Mar 1996 Pages: 295 -307
	V	Chang et al. "Transient analysis of VLSI interconnects with arbitrary initial distributions and nonlinear terminations," IEEE International Conference on Computer Design: VLSI in Computers and Processors, ICCD '94. Proceedings 10-12 Oct 1994, PP 563-566
	W	Schutt-Aine, J.E., "Latency insertion method (LIM) for the fast transient simulation of large networks," IEEE Transactions on Circuits and Systems I: Fundamental Theory and Applications, Vol.: 48 Issue: 1 , Jan 2001, Page(s): 81 –89.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.